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# LinkTest™ Dual E1

## (E1, Datacom, Jitter, Wander Testing)

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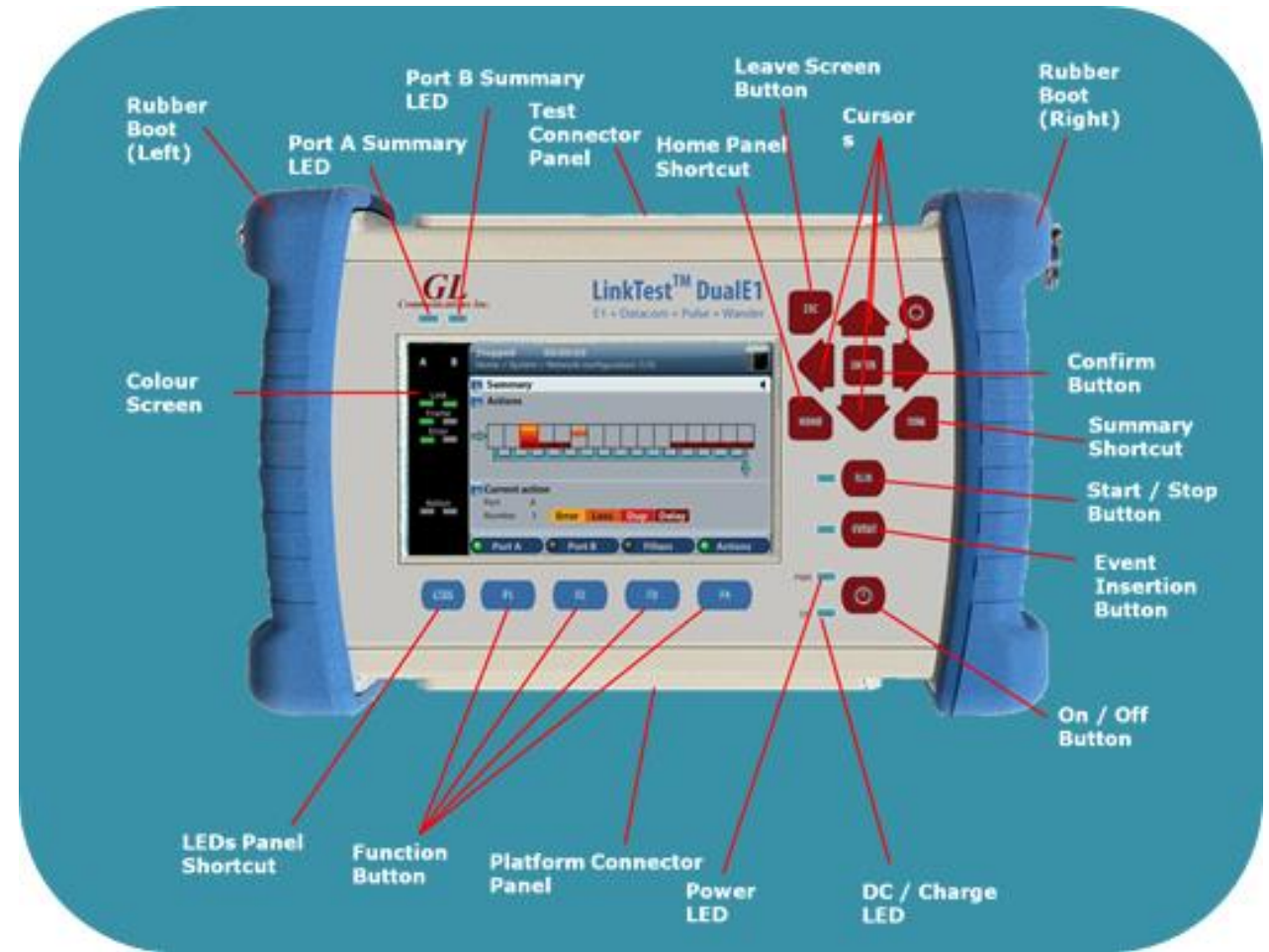
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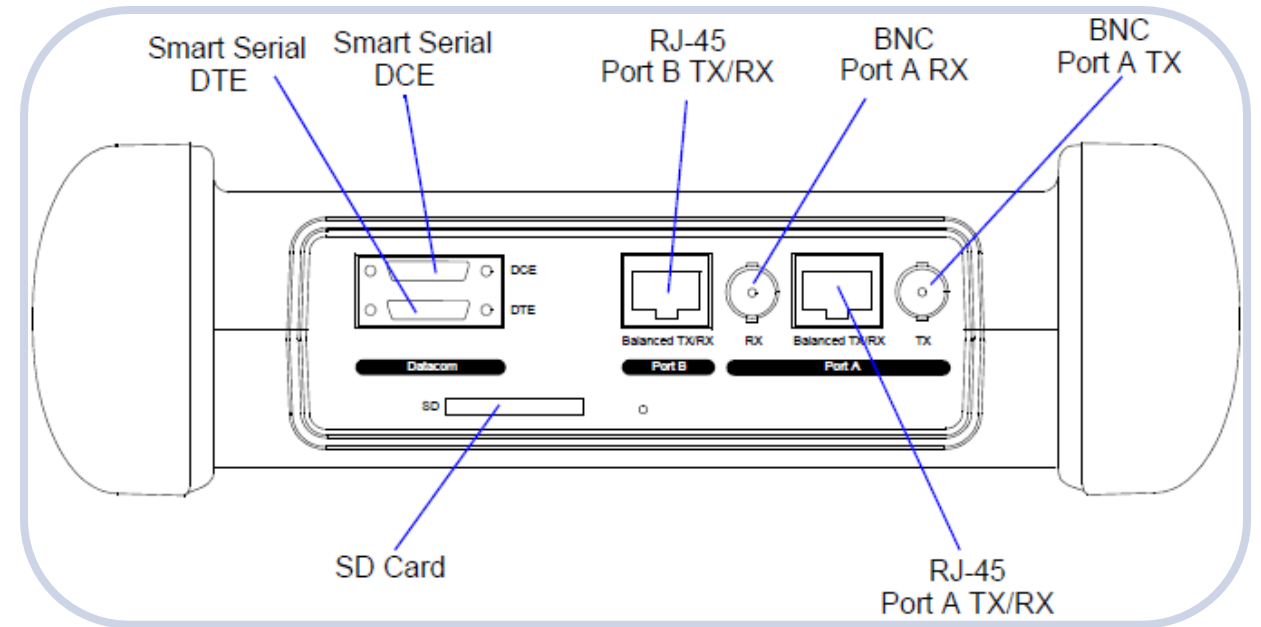
# LinkTest™ Dual E1

- Handheld (1kg), Dual-Port tester
- Longest Battery Life (16h. with 2xbatteries)
- Dimensions: 223 mm x 144 mm x 65 mm
- Generation and analysis of E1 and data communications
- Large range of software options for E1 services and sub rate multiplexing system

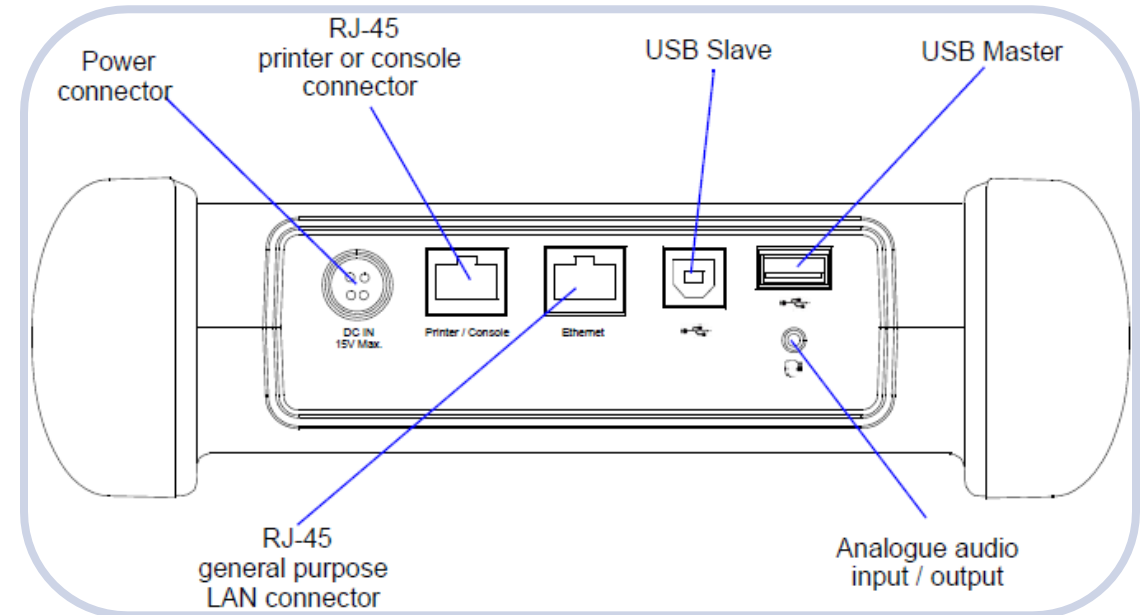


# Hardware Specifications

- Port A: Unbalanced (BNC) 75  $\Omega$  and balanced (RJ-45) 120  $\Omega$
- Port B: Balanced (RJ-45) 120  $\Omega$
- External signal: Analogue (Port A only ), 64 kb/s co-directional (Port A only)
- Universal Datacom interface for the DTE and DCE.
- Bidirectional testing (monitor, endpoint, through) by simultaneous operation of Port A and Port B
- Slot for SD Cards for external storage

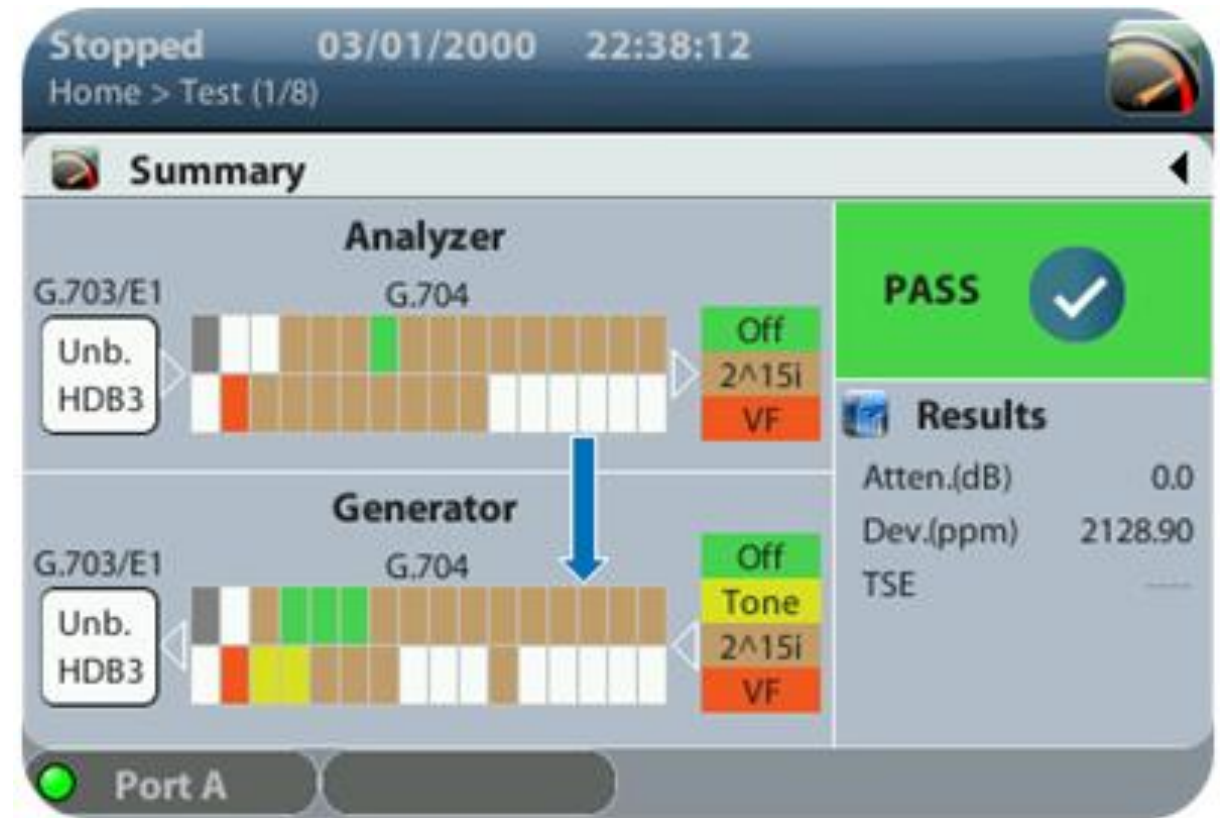


- Rugged, hand-held, battery operated, low-cost, software upgradable design for field use.
- 2xUSB and Ethernet ports.
- IP remote control through Ethernet port.
- Export stored configuration and reports through USB Master port
- Connect a PC to the tester and access to the internal tester file system.
- VF test + earphone + microphone.



# Display

- Display 480 x 272 TFT full color screen
- Limited Navigation deep
- SoftLEDs © all events at a glance
- Functional navigation keys
- Landscape ergonomony
- PASS / FAIL at a glance



# Main Features

- Supports ITU-T G.711 encoding with A law, G.703 E1 (2.048 Mbit/s), G.704, G.703 co-directional
- ITU-T G.821, G.826, and M.2100 performance analysis. Framed (as per ITU-T G.704) and unframed signals testing
- Jitter measurement as per ITU-T G.823 standard. Pulse mask testing as per ITU-T G.703 standard
- CAS signaling generation and monitoring
- Error detection and alarm generation for detecting bit errors, frame errors, signal defects and anomalies
- Error Insertion Levels - at physical level, frame level, and pattern level
- Error Insertion Modes - Single, Rate, Burst or Continuous burst. BER patterns - Multiple standard, non-standard PRBS, and user defined patterns
- VF tone generation and measurement, drop and insert. Frequency, clock slip, round trip delay, and signal level measurement

# Applications

- Installation, commissioning and maintenance of digital networks
- Manage fixed and mobile networks that are using E1 and Datacom backhaul circuits
- Digital voice and data testing, delay measurements, jitter measurement, wander measurement, pulse mask compliance
- Maintaining and troubleshooting PDH, Synchronization, and Datacom links

# Operation Modes

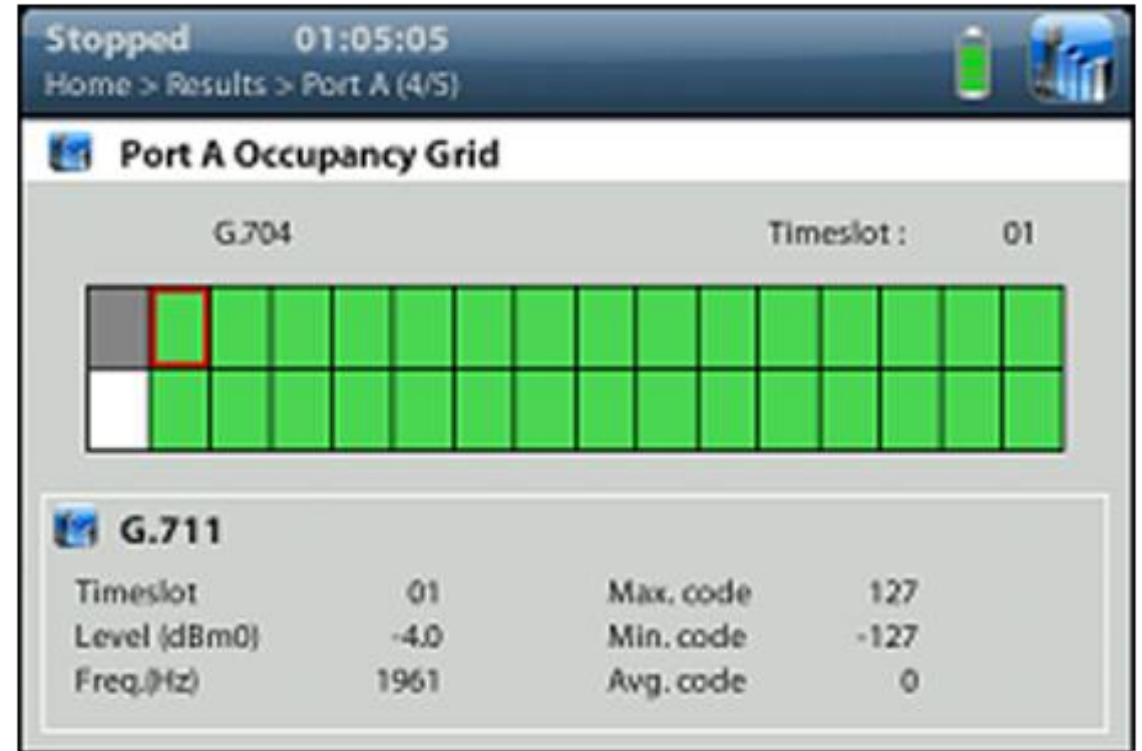
- E1 monitor – Analyzes life signals without disturbing the network. The monitor connection is suitable for performing non-intrusive monitoring
- E1 endpoint – Emulates an E1 network terminating point. The endpoint connection is suitable for tests where the LinkTest™ Dual E1 tester has to replace a network node or a complete network
- E1 through – E1 through mode is suited for unidirectional or bidirectional intrusive monitoring. The signal could be bypassed from the receiver to the transmitter without any modification but dropping/adding time slots to the signal, inserting events or modifying the FAS / NFAS and CAS time slots is also possible
- Datacom endpoint – Generates and analyzes V.24/V.28, X.21/V.11, V.35, V.36 and EIA-530 datacom signals
- Datacom monitor – Analyzes V.24/V.28, X.21/V.11, V.35, V.36 and EIA-530 datacom signals without disturbing communications between the DTE and DCE
- Codirectional – Generates and analyzes variable bit rate co-directional signals compliant with ITU-T G.703
- Analog – Generates a test audio signal in the analogue audio output



# Testing Physical Properties

# Voice Frequency Measurement

- Accepts an analogue telephone signal in its audio input and measures its frequency and signal level for each time slot
- Users can configure a threshold for the analogue measurements
- Generates a test audio signal in the analogue audio output



# Attenuation, Frequency, and Deviation results

- Analogue Results: Line attenuation (dB), frequency (Hz), frequency deviation (ppm), round trip delay ( $\mu$ s)
- Analogue results include pass / fail indications



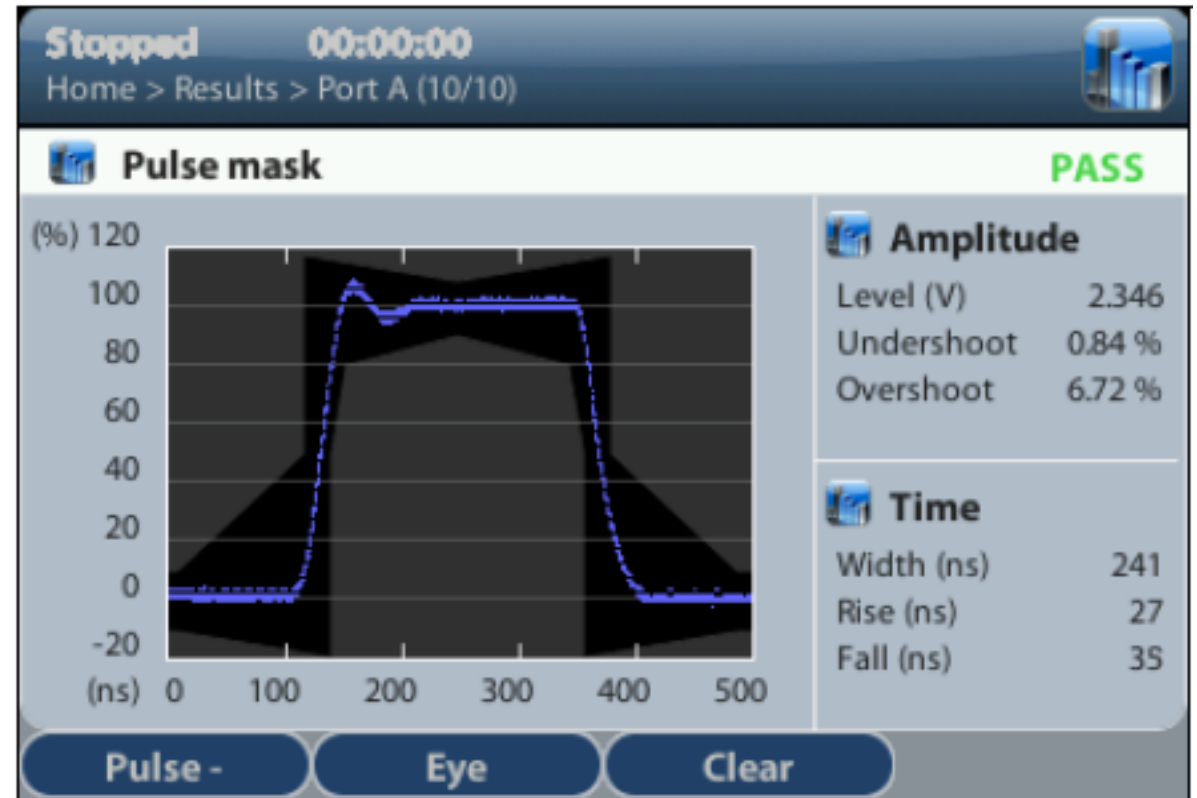
Stopped 00:00:05  
Home > Results > Port A (1/9)

**Line**

Event	Value	Units
<b>Attenuation</b>	2.0	dB
<b>Max. attenuation</b>	0.0	dB
<b>Frequency</b>	2048000.00	Hz
<b>Deviation</b>	0.00	ppm
<b>Max. deviation</b>	0.00	ppm

# Pulse Mask Compliance Testing

- Compliance: ITU-T G.703 standard for the Port A balanced and unbalanced inputs
- Operation modes - E1 monitor, E1 endpoint and E1 through modes



# Jitter Generation and Analysis

- Generate and analyze (supported on Port A only) jitter to make sure that the phase fluctuations in network equipment outputs remain under the limits specified by the standards
- Compliance: ITU-T G.825 (SDH) and G.823 (PDH), and Telcordia GR-253 (SONET) and GR-499 (T-carrier)
- Jitter measurement results: peak to peak jitter, positive peak jitter, negative peak jitter, RMS jitter, maximum jitter (user resettable), hits detection and count (user selectable threshold)
- Test the ability of a network element to attenuate or amplify phase impairments using Jitter Generation feature

# Delay Measurement

- Verify the delay in Circuit Emulation Services (CES) or legacy E1 services, data communications interfaces and the G.703 co-directional interface
- Operation modes - E1 Endpoint, E1 Through, Datacom endpoint and co-directional
- Measure Round trip delay (RTD) - aggregated delay in the forward and backward paths

# Wander Generation and Analysis

- Wander generation can be used Generate wander (Port A only) to stress network elements and see how phase modulation is accumulated as it is propagated through the network
- Open loop measurement method. Requires reference frequency
- Specify sinusoidal modulation waveform, peak-to-peak amplitude and frequency of the modulating signal
- Statistics results: Time Interval Error (TIE), Maximum TIE (MTIE), TDE

# BER Test

- Analyze different kinds of test patterns and signals - Multiple standard, non-standard PRBS, and user defined patterns
- PRBS 9 (ITU-T O.150, O.153), PRBS 11 (ITU-T O.150, O.152, O.153), PRBS 15 (ITU-T O.150, O.151), PRBS 20 (ITU-T O.150, O.153), PRBS 23 (ITU-T O.150, O.151), PRBS 9 inverted, PRBS 11 inverted, PRBS 15 inverted, PRBS 20 inverted, PRBS 23 inverted, all 0, all 1
- User configurable 32 bit word
- Individual time slots can also be inserted and dropped to a secondary low speed interface (Port B only) for its analysis by an external equipment

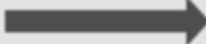



# Datacom Testing

- Add / Drop of E1 Tributaries to Datacom Interfaces
- DTE + DCE for all operation modes
- Capable of testing BER / Performance tests over datacom interfaces and logic analysis of datacom signals through datacom endpoints
- Datacom monitor mode enables analysis of datacom signals between the DTE and DCE without disturbing them
- No extra hardware's or adapters required

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Home > Results > Datacom (4/4)

 **Circuit Map** V.35

DTE <> DCE	Circuit	Signal	Activity	State
	103	TD	Active	0
	104	RD	Idle	0
	105	RTS	Idle	OFF
	106	CTS	Idle	ON
	107	DSR	Idle	ON
	108	DTR	Idle	OFF
	109	DCD	Idle	ON
	113	TTC	Active	ON
	114	TC	Idle	ON
	115	RC	Idle	ON
	141	LL	Idle	OFF

# Anomalies

- Anomalies: Code, FAS error, CRC error, REBE, MFAS error, TSE, Slip.
- Defects: LOS, LOF, AIS, RAI, CRC-LOM, CAS-LOM, MAIS, MRAI, LSS, All 0, All 1
- Live and history LEDs for all Defects and Anomalies

Event	Count	Rate	Seconds
<b>Code</b>	0	0.000e+00	0
<b>FAS</b>	0	0.000e+00	0
<b>CRC</b>	0	0.000e+00	0
<b>REBE</b>	0	0.000e+00	0
<b>MFAS</b>	0	0.000e+00	0
<b>TSE</b>	32	3.333e-06	2

**THANK YOU!**